Sheet 1 of 5

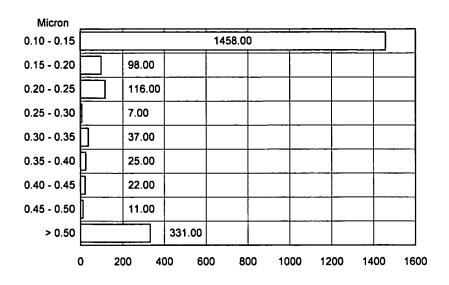


Figure 1

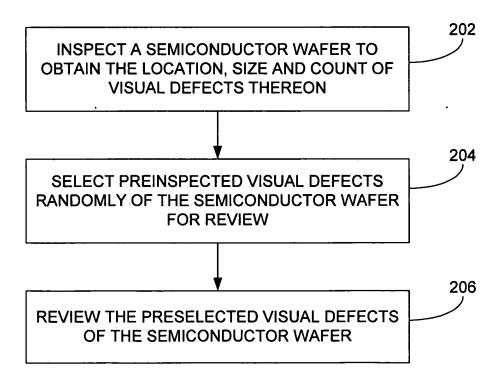
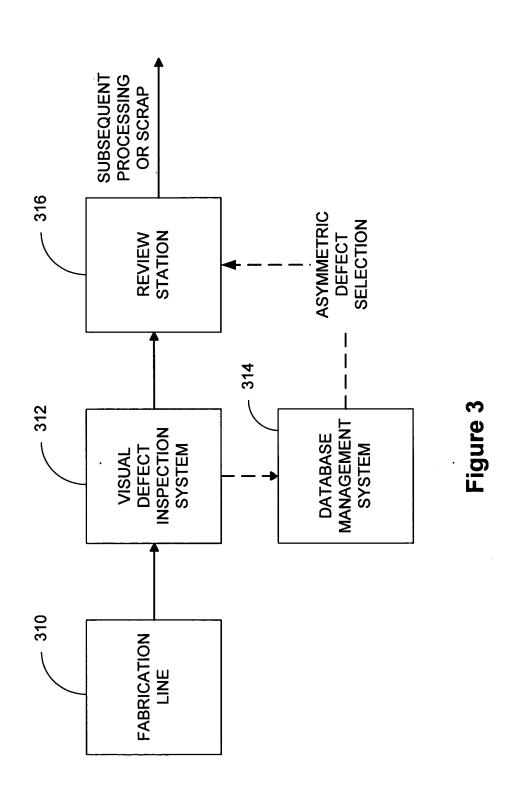


Figure 2 (Prior Art)

Sheet 2 of 5



MXIC 1555-1

Inventors: Shu-Sing Liao et al.
Title: Method and System for Analyzing
Defects of an Integrated Circuit Wafer
Attorney Docket: MXIC 1555-1

Sheet 3 of 5

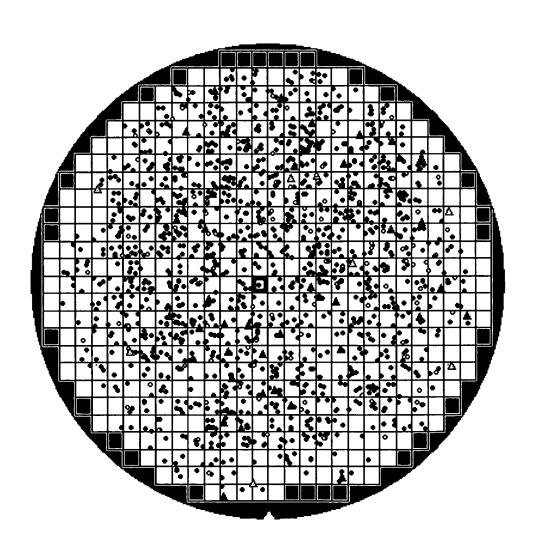


Figure 4

Sheet 4 of 5

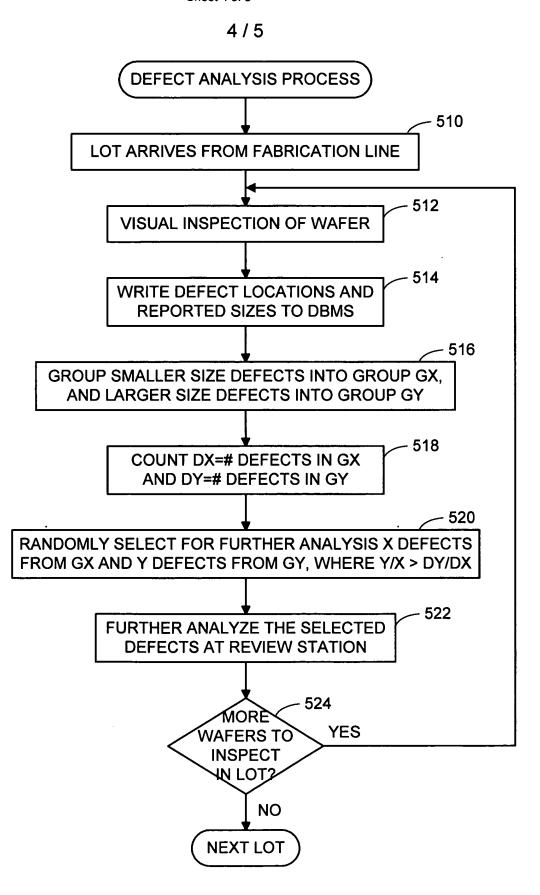


Figure 5

Sheet 5 of 5

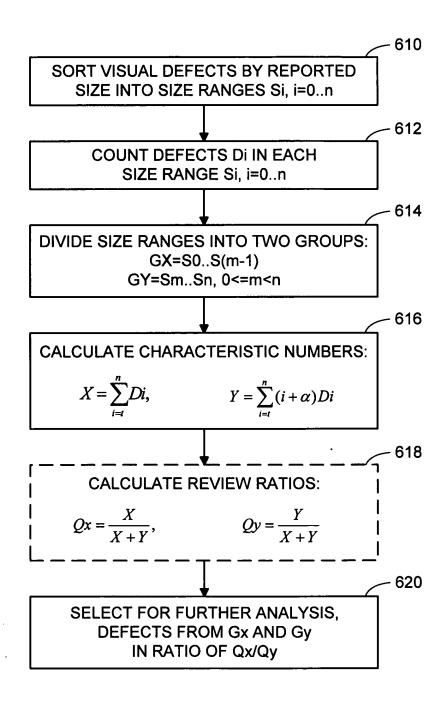


Figure 6